Most Frequently Occurring Classifications of Patents Returned From A Search of 09/990,330 on October 04, 2002

Combined Classifications

- 6 257/133
- 6 257/138
- 6 257/E29.214
- 6 257/E29.216
- 6 438/305
- 5 257/E29.257
- 4 257/378
- 4 257/412
- 4 257/E29.04
- 4 257/E29.066
- 4 438/270
- 3 257/137
- 3 257/139
- 3 257/146
- 3 257/163
- 3 257/316
- 3 257/331
- 3 257/339
- 3 257/341
- 3 257/350 3 257/401
- 3 257/E29.063
- 3 438/234 3 438/302
- 3 438/307
- 2 257/132
- 2 257/142 2 257/144
- 2 257/147
- 2 257/154
- 2 257/157
- 2 257/173
- 2 257/322
- 2 257/324
- 2 257/330
- 2 257/332
- 2 257/336
- 2 257/340
- 2 257/342 2 257/344
- 2 257/348
- 2 257/402 2 257/409
- 2 257/413
- 2 257/E29.008
- 2 257/E29.027
- 2 257/E29.054
- 2 257/E29.055
- 2 257/E29.133
- 2 257/E29.201
- 2 257/E29.26
- 2 257/E29.268 ·

- 2 257/E29.275
- 2 438/230
- 2 438/259
- 2 438/261
- 2 438/301
- 2 438/303
- 2 438/525
- 2 438/586
- 2 438/595 2 438/981

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6 257/133
               (1 OR, 5 XR)
      Class 257: ACTIVE SOLID-STATE DEVICES
                      (E) REGENERATIVE TYPE SWITCHING DEVICE (E.G.,
      257/107
                SCR, COMFET, THYRISTOR)
      257/133
                      .(E) Combined with field effect transistor
 6 257/138
               (2 OR. 4 XR)
      Class 257: ACTIVE SOLID-STATE DEVICES
      257/107
                      (E) REGENERATIVE TYPE SWITCHING DEVICE (E.G.,
                 SCR, COMFET, THYRISTOR)
                      .(E) Combined with field effect transistor
      257/133
      257/137
                      ..(E) Having controllable emitter shunt
                      ...(E) Having gate turn off (GTO) feature
      257/138
 6 257/E29.214 (0 OR, 6 XR)
      Class 257: ACTIVE SOLID-STATE DEVICES
                      ....Insulating materials for IGFET (EPO)
      257/E29.162
      257/E29.166
                      .Types of semiconductor semiconductor device (EPO)
      257/E29.169
                      .. Controllable by only signal applied to
                  control electrode (e.g., base of bipolar transistor, gate
                  of field effect transistor) (EPO)
      257/E29.171
                      ...Bipolar device (EPO)
      257/E29.211
                      ....Thyristor-type device (e.g., having
                 four-zone regenerative action) (EPO)
      257/E29.212
                      .....Gate-turn-off device (EPO)
      257/E29.213
                      .....With turn off by field effect (EPO)
     257/E29.214
                      ......Produced by insulated gate structure (EPO)
 6 257/E29.216 (0 OR, 6 XR)
      Class 257: ACTIVE SOLID-STATE DEVICES
                      ....Insulating materials for IGFET (EPO)
      257/E29.162
      257/E29.166
                      .Types of semiconductor semiconductor device (EPO)
      257/E29.169
                      .. Controllable by only signal applied to control electrode (e.g., base of bipolar
transistor, gate of field effect transistor) (EPO)
     257/E29.171
                      ...Bipolar device (EPO)
     257/E29.211
                      ....Thyristor-type device (e.g., having four-zone regenerative action) (EPO)
                      .....With turn on by field effect (EPO)
     257/E29.216
 6 438/305
               (1 OR, 5 XR)
     Class 438: SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
                      MAKING FIELD EFFECT DEVICE HAVING PAIR OF
     438/142
                  ACTIVE REGIONS SEPARATED BY GATE STRUCTURE BY FORMATION OR
                  ALTERATION OF SEMICONDUCTIVE ACTIVE REGIONS
     438/197
                      .Having insulated gate (e.g., IGFET, MISFET, MOSFET, etc.)
     438/299
                      ..Self-aligned
     438/301
                      ...Source or drain doping
     438/303
                      ....Utilizing gate sidewall structure
                      .....Plural doping steps
     438/305
 5 257/E29.257 (0 OR, 5 XR)
     Class 257: ACTIVE SOLID-STATE DEVICES
     257/E29.162
                      ....Insulating materials for IGFET (EPO)
     257/E29.166
                      .Types of semiconductor semiconductor device
                   (EPO)
     257/E29.169
                      .. Controllable by only signal applied to
                  control electrode (e.g., base of bipolar transistor, gate
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of field effect transistor) (EPO)
    257/E29.226
                     ...Unipolar device (EPO)
     257/E29.242
                     ....Field effect transistor (EPO)
                     .....With field effect produced by insulated
     257/E29.255
               gate (EPO)
     257/E29.256
                     .....With channel containing layer contacting
               drain drift region (e.g., DMOS transistor) (EPO)
                     ......Having a vertical bulk current component
    257/E29.257
              or current vertically following a trench gate, (e.g.,
              vertical power DMOS transistor) (EPO)
              (0 OR, 4 XR)
4 257/378
     Class 257: ACTIVE SOLID-STATE DEVICES
                     (E) FIELD EFFECT Device
    257/213
    257/288
                     .(E) Having insulated electrode (e.g., MOSFET,
               MOS diode)
    257/368
                     ..(E) Insulated gate field effect transistor in
               integrated circuit
    257/378
                     ...Combined with bipolar transistor
              (2 OR, 2 XR)
4 257/412
    Class 257: ACTIVE SOLID-STATE DEVICES
    257/213
                     (E) FIELD EFFECT Device
    257/288
                     .(E) Having insulated electrode (e.g., MOSFET,
               MOS diode)
    257/412
                     ..Gate electrode of refractory material (e.g.,
              polysilicon or silicide of a refractory or platinum group
              metal)
4 257/E29.04
               (0 OR. 4 XR)
    Class 257: ACTIVE SOLID-STATE DEVICES
    257/E29.001
                     DETAILS OF SEMICONDUCTOR BODIES OR ELECTRODES
                 OF SEMICONDUCTOR DEVICES ADAPTED FOR RECTIFYING.
                 AMPLIFYING, OSCILLATING OR SWITCHING, OR CAPACITORS OR
                 RESISTORS WITH AT LEAST ONE POTENTIAL-JUMP BARRIER OR
                 SURFACE BARRIER (E.G., PN JUNCTION DEPLETION LAYER OR
                 CARRIER CONCENTRATION LAYER) (EPO)
                     .Electrical characteristics due to properties
    257/E29.002
                of entire semiconductor body rather than just surface
                 region (EPO)
    257/E29.005
                     ... Characterized by specified shape or size of
                PN junction or by specified impurity concentration gradient
                within device (EPO)
                     ...With semiconductor regions connected to
    257/E29.029
               electrode carrying current to be rectified, amplified, or
               switched and such electrode being part of semiconductor
               device which comprises three or more electrodes (EPO)
                     ....Source or drain regions of field-effect
    257/E29.039
               devices (EPO)
                     .....Of field-effect transistors with insulated
    257/E29.04
              gate (EPO)
4 257/E29.066 (0 OR, 4 XR)
    Class 257: ACTIVE SOLID-STATE DEVICES
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DETAILS OF SEMICONDUCTOR BODIES OR ELECTRODES OF SEMICONDUCTOR DEVICES ADAPTED FOR RECTIFYING.

257/E29.001

PLUS Search Results for S/N 09/990,330, Searched October 04, 2002 (Top 50)

5736767	5324966	6087237	4914496	5457061
5314834	5654215	6087224	4983538	5460988
5840604	5804476	6096586	5200354	5463237
5918114	5834352	6110788	5208477	5471075
6040212	5885859	6140688	5250447	5488236
6051509	5894150	6228698	5279979	5554862
6222232	6002154	4358890	5296726	5580799
6222232	6001695	4417385	5336943	5604368
5221850	6037631	4760431	5414287	5610430
5241194	6080630	4908682	5444272	5625213